Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	pplicant(s)/Patent under eexamination	
10/721,258	CRAWFORD ET AL.	•	
Examiner	Art Unit		
Yoon-Young Kim	1723		

			
	SEAR	CHED	
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH (INCLUDING SEAR)
	DATE	EXMR
Inventor Search	11/17/2005	YK
See EAST Search History	11/18/2005	ΥK